

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/705,520	CHEN, HUNG-KUN	
Examiner	Art Unit	
Ted M. Wang	2611	•

SEARCHED					
Class	Subclass	Date	Examiner		
		-			

INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
I					
	· ·				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST - USPGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB, see attached search report				
	·			